Se	arch	Notes	5

Application/Control No.	Applicant(s)/Patent unde Reexamination	er
10/706,987	TEI ET AL.	
Examiner	Art Unit	
Helen L. Pezzuto	1713	

SEARCHED			
Class	Subclass	Date	Examiner
526	333		·
	336	3/17/2006	HP
Above	updated	9/8/2006	НР
Above	updated	3/9/2007	HP
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NO (INCLUDING SEARCI)
	DATE	EXMR
STIC STN search	2/15/2006	НР
West, Inventors search	3/17/2006	HP
West, inventors search updated	9/8/2006	HP
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